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Applications of Embedded - FPGAs

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Details

Product Status	Obsolete
Number of LABs/CLBs	234720
Number of Logic Elements/Cells	622000
Total RAM Bits	51200000
Number of I/O	552
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1152-BBGA, FCBGA
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxma7h1f35c1n

Table 5 lists the maximum allowed input overshoot voltage and the duration of the overshoot voltage as a percentage of device lifetime. The maximum allowed overshoot duration is specified as a percentage of high time over the lifetime of the device. A DC signal is equivalent to 100% of the duty cycle. For example, a signal that overshoots to 3.95 V can be at 3.95 V for only ~21% over the lifetime of the device; for a device lifetime of 10 years, the overshoot duration amounts to ~2 years.

Table 5. Maximum Allowed Overshoot During Transitions

Symbol	Description	Condition (V)	Overshoot Duration as % @ $T_J = 100^{\circ}\text{C}$	Unit
V_i (AC)	AC input voltage	3.8	100	%
		3.85	64	%
		3.9	36	%
		3.95	21	%
		4	12	%
		4.05	7	%
		4.1	4	%
		4.15	2	%
		4.2	1	%

Figure 1. Stratix V Device Overshoot Duration



Table 7. Recommended Transceiver Power Supply Operating Conditions for Stratix V GX, GS, and GT Devices (Part 2 of 2)

Symbol	Description	Devices	Minimum ⁽⁴⁾	Typical	Maximum ⁽⁴⁾	Unit
V_{CCR_GXBR} (2)	Receiver analog power supply (right side)	GX, GS, GT	0.82	0.85	0.88	V
			0.87	0.90	0.93	
			0.97	1.0	1.03	
			1.03	1.05	1.07	
V_{CCR_GTBR}	Receiver analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V
V_{CCT_GXBL} (2)	Transmitter analog power supply (left side)	GX, GS, GT	0.82	0.85	0.88	V
			0.87	0.90	0.93	
			0.97	1.0	1.03	
			1.03	1.05	1.07	
V_{CCT_GXBR} (2)	Transmitter analog power supply (right side)	GX, GS, GT	0.82	0.85	0.88	V
			0.87	0.90	0.93	
			0.97	1.0	1.03	
			1.03	1.05	1.07	
V_{CCT_GTBR}	Transmitter analog power supply for GT channels (right side)	GT	1.02	1.05	1.08	V
V_{CCL_GTBR}	Transmitter clock network power supply	GT	1.02	1.05	1.08	V
V_{CCH_GXBL}	Transmitter output buffer power supply (left side)	GX, GS, GT	1.425	1.5	1.575	V
V_{CCH_GXBR}	Transmitter output buffer power supply (right side)	GX, GS, GT	1.425	1.5	1.575	V

Notes to Table 7:

- (1) This supply must be connected to 3.0 V if the CMU PLL, receiver CDR, or both, are configured at a base data rate > 6.5 Gbps. Up to 6.5 Gbps, you can connect this supply to either 3.0 V or 2.5 V.
- (2) Refer to Table 8 to select the correct power supply level for your design.
- (3) When using ATX PLLs, the supply must be 3.0 V.
- (4) This value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

I/O Pin Leakage Current

Table 9 lists the Stratix V I/O pin leakage current specifications.

Table 9. I/O Pin Leakage Current for Stratix V Devices ⁽¹⁾

Symbol	Description	Conditions	Min	Typ	Max	Unit
I_I	Input pin	$V_I = 0 \text{ V to } V_{CCIOMAX}$	-30	—	30	μA
I_{OZ}	Tri-stated I/O pin	$V_O = 0 \text{ V to } V_{CCIOMAX}$	-30	—	30	μA

Note to Table 9:

(1) If $V_O = V_{CCIO}$ to $V_{CCIOMAX}$, 100 μA of leakage current per I/O is expected.

Bus Hold Specifications

Table 10 lists the Stratix V device family bus hold specifications.

Table 10. Bus Hold Parameters for Stratix V Devices

Parameter	Symbol	Conditions	V _{CCIO}										Unit
			1.2 V		1.5 V		1.8 V		2.5 V		3.0 V		
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	I _{SUSL}	V _{IN} > V _{IL} (maximum)	22.5	—	25.0	—	30.0	—	50.0	—	70.0	—	μA
High sustaining current	I _{SUSH}	V _{IN} < V _{IH} (minimum)	−22.5	—	−25.0	—	−30.0	—	−50.0	—	−70.0	—	μA
Low overdrive current	I _{ODL}	0V < V _{IN} < V _{CCIO}	—	120	—	160	—	200	—	300	—	500	μA
High overdrive current	I _{ODH}	0V < V _{IN} < V _{CCIO}	—	−120	—	−160	—	−200	—	−300	—	−500	μA
Bus-hold trip point	V _{TRIP}	—	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

On-Chip Termination (OCT) Specifications

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block. Table 11 lists the Stratix V OCT termination calibration accuracy specifications.

Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices ⁽¹⁾ (Part 1 of 2)

Symbol	Description	Conditions	Calibration Accuracy				Unit
			C1	C2,I2	C3,I3, I3YY	C4,I4	
25- Ω R_S	Internal series termination with calibration (25- Ω setting)	$V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 \text{ V}$	± 15	± 15	± 15	± 15	%

Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices ⁽¹⁾ (Part 2 of 2)

Symbol	Description	Conditions	Calibration Accuracy				Unit
			C1	C2,I2	C3,I3,I3YY	C4,I4	
50-Ω R _S	Internal series termination with calibration (50-Ω setting)	V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%
34-Ω and 40-Ω R _S	Internal series termination with calibration (34-Ω and 40-Ω setting)	V _{CCIO} = 1.5, 1.35, 1.25, 1.2 V	±15	±15	±15	±15	%
48-Ω, 60-Ω, 80-Ω, and 240-Ω R _S	Internal series termination with calibration (48-Ω, 60-Ω, 80-Ω, and 240-Ω setting)	V _{CCIO} = 1.2 V	±15	±15	±15	±15	%
50-Ω R _T	Internal parallel termination with calibration (50-Ω setting)	V _{CCIO} = 2.5, 1.8, 1.5, 1.2 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
20-Ω, 30-Ω, 40-Ω, 60-Ω, and 120-Ω R _T	Internal parallel termination with calibration (20-Ω, 30-Ω, 40-Ω, 60-Ω, and 120-Ω setting)	V _{CCIO} = 1.5, 1.35, 1.25 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
60-Ω and 120-Ω R _T	Internal parallel termination with calibration (60-Ω and 120-Ω setting)	V _{CCIO} = 1.2	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%
25-Ω R _{S_left_shift}	Internal left shift series termination with calibration (25-Ω R _{S_left_shift} setting)	V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%

Note to Table 11:

(1) OCT calibration accuracy is valid at the time of calibration only.

Table 12 lists the Stratix V OCT without calibration resistance tolerance to PVT changes.

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 1 of 2)

Symbol	Description	Conditions	Resistance Tolerance				Unit
			C1	C2,I2	C3, I3, I3YY	C4, I4	
25-Ω R, 50-Ω R _S	Internal series termination without calibration (25-Ω setting)	V _{CCIO} = 3.0 and 2.5 V	±30	±30	±40	±40	%
25-Ω R _S	Internal series termination without calibration (25-Ω setting)	V _{CCIO} = 1.8 and 1.5 V	±30	±30	±40	±40	%
25-Ω R _S	Internal series termination without calibration (25-Ω setting)	V _{CCIO} = 1.2 V	±35	±35	±50	±50	%

Table 18. Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications for Stratix V Devices

I/O Standard	V_{CCIO} (V)			V_{REF} (V)			V_{TT} (V)		
	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$	$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$
SSTL-18 Class I, II	1.71	1.8	1.89	0.833	0.9	0.969	$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$
SSTL-15 Class I, II	1.425	1.5	1.575	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$
SSTL-135 Class I, II	1.283	1.35	1.418	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$
SSTL-125 Class I, II	1.19	1.25	1.26	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$
SSTL-12 Class I, II	1.14	1.20	1.26	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$
HSTL-18 Class I, II	1.71	1.8	1.89	0.85	0.9	0.95	—	$V_{CCIO}/2$	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.68	0.75	0.9	—	$V_{CCIO}/2$	—
HSTL-12 Class I, II	1.14	1.2	1.26	$0.47 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.53 * V_{CCIO}$	—	$V_{CCIO}/2$	—
HSUL-12	1.14	1.2	1.3	$0.49 * V_{CCIO}$	$0.5 * V_{CCIO}$	$0.51 * V_{CCIO}$	—	—	—

Table 19. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Stratix V Devices (Part 1 of 2)

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OI} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-2 Class I	-0.3	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$V_{CCIO} + 0.3$	$V_{REF} - 0.31$	$V_{REF} + 0.31$	$V_{TT} - 0.608$	$V_{TT} + 0.608$	8.1	-8.1
SSTL-2 Class II	-0.3	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$V_{CCIO} + 0.3$	$V_{REF} - 0.31$	$V_{REF} + 0.31$	$V_{TT} - 0.81$	$V_{TT} + 0.81$	16.2	-16.2
SSTL-18 Class I	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCIO} + 0.3$	$V_{REF} - 0.25$	$V_{REF} + 0.25$	$V_{TT} - 0.603$	$V_{TT} + 0.603$	6.7	-6.7
SSTL-18 Class II	-0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCIO} + 0.3$	$V_{REF} - 0.25$	$V_{REF} + 0.25$	0.28	$V_{CCIO} - 0.28$	13.4	-13.4
SSTL-15 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.175$	$V_{REF} + 0.175$	$0.2 * V_{CCIO}$	$0.8 * V_{CCIO}$	8	-8
SSTL-15 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.175$	$V_{REF} + 0.175$	$0.2 * V_{CCIO}$	$0.8 * V_{CCIO}$	16	-16
SSTL-135 Class I, II	—	$V_{REF} - 0.09$	$V_{REF} + 0.09$	—	$V_{REF} - 0.16$	$V_{REF} + 0.16$	$0.2 * V_{CCIO}$	$0.8 * V_{CCIO}$	—	—
SSTL-125 Class I, II	—	$V_{REF} - 0.85$	$V_{REF} + 0.85$	—	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.2 * V_{CCIO}$	$0.8 * V_{CCIO}$	—	—
SSTL-12 Class I, II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.2 * V_{CCIO}$	$0.8 * V_{CCIO}$	—	—

Switching Characteristics

This section provides performance characteristics of the Stratix V core and periphery blocks.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The title of these tables show the designation as “Preliminary.”
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

Transceiver Performance Specifications

This section describes transceiver performance specifications.

Table 23 lists the Stratix V GX and GS transceiver specifications.

Table 23. Transceiver Specifications for Stratix V GX and GS Devices ⁽¹⁾ (Part 1 of 7)

Symbol/ Description	Conditions	Transceiver Speed Grade 1			Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Reference Clock											
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL									
	RX reference clock pin	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS									
Input Reference Clock Frequency (CMU PLL) ⁽⁸⁾	—	40	—	710	40	—	710	40	—	710	MHz
Input Reference Clock Frequency (ATX PLL) ⁽⁸⁾	—	100	—	710	100	—	710	100	—	710	MHz
Rise time	Measure at ±60 mV of differential signal ⁽²⁶⁾	—	—	400	—	—	400	—	—	400	ps
Fall time	Measure at ±60 mV of differential signal ⁽²⁶⁾	—	—	400	—	—	400	—	—	400	
Duty cycle	—	45	—	55	45	—	55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express® (PCIe®)	30	—	33	30	—	33	30	—	33	kHz

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 1 of 5) ⁽¹⁾

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Reference Clock								
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCML, 1.4-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL						
	RX reference clock pin	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS						
Input Reference Clock Frequency (CMU PLL) ⁽⁶⁾	—	40	—	710	40	—	710	MHz
Input Reference Clock Frequency (ATX PLL) ⁽⁶⁾	—	100	—	710	100	—	710	MHz
Rise time	20% to 80%	—	—	400	—	—	400	ps
Fall time	80% to 20%	—	—	400	—	—	400	
Duty cycle	—	45	—	55	45	—	55	%
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30	—	33	30	—	33	kHz
Spread-spectrum downspread	PCIe	—	0 to −0.5	—	—	0 to −0.5	—	%
On-chip termination resistors ⁽¹⁹⁾	—	—	100	—	—	100	—	Ω
Absolute V _{MAX} ⁽³⁾	Dedicated reference clock pin	—	—	1.6	—	—	1.6	V
	RX reference clock pin	—	—	1.2	—	—	1.2	
Absolute V _{MIN}	—	-0.4	—	—	-0.4	—	—	V
Peak-to-peak differential input voltage	—	200	—	1600	200	—	1600	mV
V _{ICM} (AC coupled)	Dedicated reference clock pin	1050/1000 ⁽²⁾			1050/1000 ⁽²⁾			mV
	RX reference clock pin	1.0/0.9/0.85 ⁽²²⁾			1.0/0.9/0.85 ⁽²²⁾			V
V _{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	mV

Table 28. Transceiver Specifications for Stratix V GT Devices (Part 3 of 5) ⁽¹⁾

Symbol/ Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Differential on-chip termination resistors ⁽⁷⁾	GT channels	—	100	—	—	100	—	Ω
Differential on-chip termination resistors for GX channels ⁽¹⁹⁾	85- Ω setting	—	85 \pm 30%	—	—	85 \pm 30%	—	Ω
	100- Ω setting	—	100 \pm 30%	—	—	100 \pm 30%	—	Ω
	120- Ω setting	—	120 \pm 30%	—	—	120 \pm 30%	—	Ω
	150- Ω setting	—	150 \pm 30%	—	—	150 \pm 30%	—	Ω
V _{ICM} (AC coupled)	GT channels	—	650	—	—	650	—	mV
VICM (AC and DC coupled) for GX Channels	VCCR_GXB = 0.85 V or 0.9 V	—	600	—	—	600	—	mV
	VCCR_GXB = 1.0 V full bandwidth	—	700	—	—	700	—	mV
	VCCR_GXB = 1.0 V half bandwidth	—	750	—	—	750	—	mV
t _{LTR} ⁽⁹⁾	—	—	—	10	—	—	10	μ s
t _{LTD} ⁽¹⁰⁾	—	4	—	—	4	—	—	μ s
t _{LTD_manual} ⁽¹¹⁾	—	4	—	—	4	—	—	μ s
t _{LTR_LTD_manual} ⁽¹²⁾	—	15	—	—	15	—	—	μ s
Run Length	GT channels	—	—	72	—	—	72	CID
	GX channels	⁽⁸⁾						
CDR PPM	GT channels	—	—	1000	—	—	1000	\pm PPM
	GX channels	⁽⁸⁾						
Programmable equalization (AC Gain) ⁽⁵⁾	GT channels	—	—	14	—	—	14	dB
	GX channels	⁽⁸⁾						
Programmable DC gain ⁽⁶⁾	GT channels	—	—	7.5	—	—	7.5	dB
	GX channels	⁽⁸⁾						
Differential on-chip termination resistors ⁽⁷⁾	GT channels	—	100	—	—	100	—	Ω
Transmitter								
Supported I/O Standards	—	1.4-V and 1.5-V PCML						
Data rate (Standard PCS)	GX channels	600	—	8500	600	—	8500	Mbps
Data rate (10G PCS)	GX channels	600	—	12,500	600	—	12,500	Mbps

Table 29 shows the V_{OD} settings for the GT channel.

Table 29. Typical V_{OD} Setting for GT Channel, TX Termination = 100 Ω

Symbol	V_{OD} Setting	V_{OD} Value (mV)
V_{OD} differential peak to peak typical ⁽¹⁾	0	0
	1	200
	2	400
	3	600
	4	800
	5	1000

Note:

(1) Refer to Figure 4.

PLL Specifications

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to 85°C) and the industrial junction temperature range (–40° to 100°C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

Symbol	Parameter	Min	Typ	Max	Unit
f_{IN}	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5	—	800 ⁽¹⁾	MHz
	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5	—	800 ⁽¹⁾	MHz
	Input clock frequency (C4, I4 speed grades)	5	—	650 ⁽¹⁾	MHz
f_{INPFD}	Input frequency to the PFD	5	—	325	MHz
f_{FINPFD}	Fractional Input clock frequency to the PFD	50	—	160	MHz
f_{VCO} ⁽⁹⁾	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	—	1600	MHz
	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600	—	1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	—	1300	MHz
$t_{EINDUTY}$	Input clock or external feedback clock input duty cycle	40	—	60	%
f_{OUT}	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)	—	—	717 ⁽²⁾	MHz
	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)	—	—	650 ⁽²⁾	MHz
	Output frequency for an internal global or regional clock (C4, I4 speed grades)	—	—	580 ⁽²⁾	MHz
f_{OUT_EXT}	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)	—	—	800 ⁽²⁾	MHz
	Output frequency for an external clock output (C3, I3, I3L speed grades)	—	—	667 ⁽²⁾	MHz
	Output frequency for an external clock output (C4, I4 speed grades)	—	—	553 ⁽²⁾	MHz
$t_{OUTDUTY}$	Duty cycle for a dedicated external clock output (when set to 50%)	45	50	55	%
t_{FCOMP}	External feedback clock compensation time	—	—	10	ns
$f_{DYCONFIGCLK}$	Dynamic Configuration Clock used for <code>mgmt_clk</code> and <code>scanclk</code>	—	—	100	MHz
t_{LOCK}	Time required to lock from the end-of-device configuration or deassertion of <code>areset</code>	—	—	1	ms
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	—	—	1	ms
f_{CLBW}	PLL closed-loop low bandwidth	—	0.3	—	MHz
	PLL closed-loop medium bandwidth	—	1.5	—	MHz
	PLL closed-loop high bandwidth ⁽⁷⁾	—	4	—	MHz
t_{PLL_PSERR}	Accuracy of PLL phase shift	—	—	±50	ps
t_{ARESET}	Minimum pulse width on the <code>areset</code> signal	10	—	—	ns

Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)

Symbol	Parameter	Min	Typ	Max	Unit
t_{INCCJ} ^{(3), (4)}	Input clock cycle-to-cycle jitter ($f_{\text{REF}} \geq 100$ MHz)	—	—	0.15	UI (p-p)
	Input clock cycle-to-cycle jitter ($f_{\text{REF}} < 100$ MHz)	−750	—	+750	ps (p-p)
$t_{\text{OUTPJ_DC}}$ ⁽⁵⁾	Period Jitter for dedicated clock output ($f_{\text{OUT}} \geq 100$ MHz)	—	—	175 ⁽¹⁾	ps (p-p)
	Period Jitter for dedicated clock output ($f_{\text{OUT}} < 100$ MHz)	—	—	17.5 ⁽¹⁾	mUI (p-p)
$t_{\text{FOUTPJ_DC}}$ ⁽⁵⁾	Period Jitter for dedicated clock output in fractional PLL ($f_{\text{OUT}} \geq 100$ MHz)	—	—	250 ⁽¹¹⁾ , 175 ⁽¹²⁾	ps (p-p)
	Period Jitter for dedicated clock output in fractional PLL ($f_{\text{OUT}} < 100$ MHz)	—	—	25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾	mUI (p-p)
$t_{\text{OUTCCJ_DC}}$ ⁽⁵⁾	Cycle-to-Cycle Jitter for a dedicated clock output ($f_{\text{OUT}} \geq 100$ MHz)	—	—	175	ps (p-p)
	Cycle-to-Cycle Jitter for a dedicated clock output ($f_{\text{OUT}} < 100$ MHz)	—	—	17.5	mUI (p-p)
$t_{\text{FOUTCCJ_DC}}$ ⁽⁵⁾	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{\text{OUT}} \geq 100$ MHz)	—	—	250 ⁽¹¹⁾ , 175 ⁽¹²⁾	ps (p-p)
	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{\text{OUT}} < 100$ MHz)+	—	—	25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾	mUI (p-p)
$t_{\text{OUTPJ_IO}}$ ^{(5), (8)}	Period Jitter for a clock output on a regular I/O in integer PLL ($f_{\text{OUT}} \geq 100$ MHz)	—	—	600	ps (p-p)
	Period Jitter for a clock output on a regular I/O ($f_{\text{OUT}} < 100$ MHz)	—	—	60	mUI (p-p)
$t_{\text{FOUTPJ_IO}}$ ^{(5), (8), (11)}	Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{\text{OUT}} \geq 100$ MHz)	—	—	600 ⁽¹⁰⁾	ps (p-p)
	Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{\text{OUT}} < 100$ MHz)	—	—	60 ⁽¹⁰⁾	mUI (p-p)
$t_{\text{OUTCCJ_IO}}$ ^{(5), (8)}	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{\text{OUT}} \geq 100$ MHz)	—	—	600	ps (p-p)
	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{\text{OUT}} < 100$ MHz)	—	—	60 ⁽¹⁰⁾	mUI (p-p)
$t_{\text{FOUTCCJ_IO}}$ ^{(5), (8), (11)}	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{\text{OUT}} \geq 100$ MHz)	—	—	600 ⁽¹⁰⁾	ps (p-p)
	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{\text{OUT}} < 100$ MHz)	—	—	60	mUI (p-p)
$t_{\text{CASC_OUTPJ_DC}}$ ^{(5), (6)}	Period Jitter for a dedicated clock output in cascaded PLLs ($f_{\text{OUT}} \geq 100$ MHz)	—	—	175	ps (p-p)
	Period Jitter for a dedicated clock output in cascaded PLLs ($f_{\text{OUT}} < 100$ MHz)	—	—	17.5	mUI (p-p)
f_{DRIFT}	Frequency drift after PFDENA is disabled for a duration of 100 μ s	—	—	± 10	%
dK_{BIT}	Bit number of Delta Sigma Modulator (DSM)	8	24	32	Bits
k_{VALUE}	Numerator of Fraction	128	8388608	2147483648	—

Table 32. Block Performance Specifications for Stratix V DSP Devices (Part 2 of 2)

Mode	Peformance							Unit
	C1	C2, C2L	I2, I2L	C3	I3, I3L, I3YY	C4	I4	
Modes using Three DSPs								
One complex 18 x 25	425	425	415	340	340	275	265	MHz
Modes using Four DSPs								
One complex 27 x 27	465	465	465	380	380	300	290	MHz

Memory Block Specifications

Table 33 lists the Stratix V memory block specifications.

Table 33. Memory Block Performance Specifications for Stratix V Devices ⁽¹⁾, ⁽²⁾ (Part 1 of 2)

Memory	Mode	Resources Used		Performance							Unit
		ALUTs	Memory	C1	C2, C2L	C3	C4	I2, I2L	I3, I3L, I3YY	I4	
MLAB	Single port, all supported widths	0	1	450	450	400	315	450	400	315	MHz
	Simple dual-port, x32/x64 depth	0	1	450	450	400	315	450	400	315	MHz
	Simple dual-port, x16 depth ⁽³⁾	0	1	675	675	533	400	675	533	400	MHz
	ROM, all supported widths	0	1	600	600	500	450	600	500	450	MHz

Periphery Performance

This section describes periphery performance, including high-speed I/O and external memory interface.

I/O performance supports several system interfaces, such as the **LVDS** high-speed I/O interface, external memory interface, and the **PCI/PCI-X** bus interface.

General-purpose I/O standards such as 3.3-, 2.5-, 1.8-, and 1.5-**LVTTL/LVCMOS** are capable of a typical 167 MHz and 1.2-**LVCMOS** at 100 MHz interfacing frequency with a 10 pF load.



The actual achievable frequency depends on design- and system-specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 36 lists high-speed I/O timing for Stratix V devices.

Table 36. High-Speed I/O Specifications for Stratix V Devices ⁽¹⁾, ⁽²⁾ (Part 1 of 4)

Symbol	Conditions	C1			C2, C2L, I2, I2L			C3, I3, I3L, I3YY			C4,I4			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$f_{\text{HCLK_in}}$ (input clock frequency) True Differential I/O Standards	Clock boost factor $W = 1$ to 40 ⁽⁴⁾	5	—	800	5	—	800	5	—	625	5	—	525	MHz
$f_{\text{HCLK_in}}$ (input clock frequency) Single Ended I/O Standards ⁽³⁾	Clock boost factor $W = 1$ to 40 ⁽⁴⁾	5	—	800	5	—	800	5	—	625	5	—	525	MHz
$f_{\text{HCLK_in}}$ (input clock frequency) Single Ended I/O Standards	Clock boost factor $W = 1$ to 40 ⁽⁴⁾	5	—	520	5	—	520	5	—	420	5	—	420	MHz
$f_{\text{HCLK_OUT}}$ (output clock frequency)	—	5	—	800	5	—	800	5	—	625 ⁽⁵⁾	5	—	525 ⁽⁵⁾	MHz

Duty Cycle Distortion (DCD) Specifications

Table 44 lists the worst-case DCD for Stratix V devices.

Table 44. Worst-Case DCD on Stratix V I/O Pins ⁽¹⁾

Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4, I4		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
Output Duty Cycle	45	55	45	55	45	55	45	55	%

Note to Table 44:

(1) The DCD numbers do not cover the core clock network.

Configuration Specification

POR Delay Specification

Power-on reset (POR) delay is defined as the delay between the time when all the power supplies monitored by the POR circuitry reach the minimum recommended operating voltage to the time when the nSTATUS is released high and your device is ready to begin configuration.



For more information about the POR delay, refer to the *Hot Socketing and Power-On Reset in Stratix V Devices* chapter.

Table 45 lists the fast and standard POR delay specification.

Table 45. Fast and Standard POR Delay Specification ⁽¹⁾

POR Delay	Minimum	Maximum
Fast	4 ms	12 ms
Standard	100 ms	300 ms

Note to Table 45:

(1) You can select the POR delay based on the MSEL settings as described in the MSEL Pin Settings section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

JTAG Configuration Specifications

Table 46 lists the JTAG timing parameters and values for Stratix V devices.

Table 46. JTAG Timing Parameters and Values for Stratix V Devices

Symbol	Description	Min	Max	Unit
t _{JCP}	TCK clock period ⁽²⁾	30	—	ns
t _{JCP}	TCK clock period ⁽²⁾	167	—	ns
t _{JCH}	TCK clock high time ⁽²⁾	14	—	ns
t _{JCL}	TCK clock low time ⁽²⁾	14	—	ns
t _{JPSU (TDI)}	TDI JTAG port setup time	2	—	ns
t _{JPSU (TMS)}	TMS JTAG port setup time	3	—	ns

Table 50 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA [] ratio is 1.

Table 50. FPP Timing Parameters for Stratix V Devices ⁽¹⁾

Symbol	Parameter	Minimum	Maximum	Units
t _{CF2CD}	nCONFIG low to CONF_DONE low	—	600	ns
t _{CF2ST0}	nCONFIG low to nSTATUS low	—	600	ns
t _{CFG}	nCONFIG low pulse width	2	—	μs
t _{STATUS}	nSTATUS low pulse width	268	1,506 ⁽²⁾	μs
t _{CF2ST1}	nCONFIG high to nSTATUS high	—	1,506 ⁽³⁾	μs
t _{CF2CK} ⁽⁶⁾	nCONFIG high to first rising edge on DCLK	1,506	—	μs
t _{ST2CK} ⁽⁶⁾	nSTATUS high to first rising edge of DCLK	2	—	μs
t _{DSU}	DATA [] setup time before rising edge on DCLK	5.5	—	ns
t _{DH}	DATA [] hold time after rising edge on DCLK	0	—	ns
t _{CH}	DCLK high time	$0.45 \times 1/f_{\text{MAX}}$	—	s
t _{CL}	DCLK low time	$0.45 \times 1/f_{\text{MAX}}$	—	s
t _{CLK}	DCLK period	$1/f_{\text{MAX}}$	—	s
f _{MAX}	DCLK frequency (FPP $\times 8/\times 16$)	—	125	MHz
	DCLK frequency (FPP $\times 32$)	—	100	MHz
t _{CD2UM}	CONF_DONE high to user mode ⁽⁴⁾	175	437	μs
t _{CD2CU}	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
t _{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t _{CD2CU} + (8576 × CLKUSR period) ⁽⁵⁾	—	—

Notes to Table 50:

- (1) Use these timing parameters when the decompression and design security features are disabled.
- (2) This value is applicable if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) This value is applicable if you do not delay configuration by externally holding the nSTATUS low.
- (4) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.
- (5) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.
- (6) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.

FPP Configuration Timing when DCLK-to-DATA [] > 1

Figure 13 shows the timing waveform for FPP configuration when using a MAX II device, MAX V device, or microprocessor as an external host. This waveform shows timing when the DCLK-to-DATA [] ratio is more than 1.

Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA [] ratio is more than 1.

Table 51. FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is >1 ⁽¹⁾

Symbol	Parameter	Minimum	Maximum	Units
t_{CF2CD}	nCONFIG low to CONF_DONE low	—	600	ns
t_{CF2ST0}	nCONFIG low to nSTATUS low	—	600	ns
t_{CFG}	nCONFIG low pulse width	2	—	μ s
t_{STATUS}	nSTATUS low pulse width	268	1,506 ⁽²⁾	μ s
t_{CF2ST1}	nCONFIG high to nSTATUS high	—	1,506 ⁽²⁾	μ s
t_{CF2CK} ⁽⁵⁾	nCONFIG high to first rising edge on DCLK	1,506	—	μ s
t_{ST2CK} ⁽⁵⁾	nSTATUS high to first rising edge of DCLK	2	—	μ s
t_{DSU}	DATA [] setup time before rising edge on DCLK	5.5	—	ns
t_{DH}	DATA [] hold time after rising edge on DCLK	$N-1/f_{DCLK}$ ⁽⁵⁾	—	s
t_{CH}	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	DCLK period	$1/f_{MAX}$	—	s
f_{MAX}	DCLK frequency (FPP $\times 8/\times 16$)	—	125	MHz
	DCLK frequency (FPP $\times 32$)	—	100	MHz
t_R	Input rise time	—	40	ns
t_F	Input fall time	—	40	ns
t_{CD2UM}	CONF_DONE high to user mode ⁽³⁾	175	437	μ s
t_{CD2CU}	CONF_DONE high to CLKUSR enabled	$4 \times$ maximum DCLK period	—	—
t_{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU} + (8576 \times \text{CLKUSR period})$ ⁽⁴⁾	—	—

Notes to Table 51:

- (1) Use these timing parameters when you use the decompression and design security features.
- (2) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.
- (5) N is the DCLK-to-DATA ratio and f_{DCLK} is the DCLK frequency the system is operating.
- (6) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.

Active Serial Configuration Timing

Table 52 lists the DCLK frequency specification in the AS configuration scheme.

Table 52. DCLK Frequency Specification in the AS Configuration Scheme ^{(1), (2)}

Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz
10.6	15.7	25.0	MHz
21.3	31.4	50.0	MHz
42.6	62.9	100.0	MHz

Notes to Table 52:

- (1) This applies to the DCLK frequency specification when using the internal oscillator as the configuration clock source.
- (2) The AS multi-device configuration scheme does not support DCLK frequency of 100 MHz.

Figure 14 shows the single-device configuration setup for an AS ×1 mode.

Figure 14. AS Configuration Timing



Notes to Figure 14:

- (1) If you are using AS ×4 mode, this signal represents the AS_DATA [3 : 0] and EPCQ sends in 4-bits of data for each DCLK cycle.
- (2) The initialization clock can be from internal oscillator or CLKUSR pin.
- (3) After the option bit to enable the INIT_DONE pin is configured into the device, the INIT_DONE goes low.

Table 53 lists the timing parameters for AS ×1 and AS ×4 configurations in Stratix V devices.

Table 53. AS Timing Parameters for AS ×1 and AS ×4 Configurations in Stratix V Devices ^{(1), (2)} (Part 1 of 2)

Symbol	Parameter	Minimum	Maximum	Units
t_{CO}	DCLK falling edge to AS_DATA0/ASDO output	—	2	ns
t_{SU}	Data setup time before falling edge on DCLK	1.5	—	ns
t_H	Data hold time after falling edge on DCLK	0	—	ns

Table 53. AS Timing Parameters for AS ×1 and AS ×4 Configurations in Stratix V Devices ^{(1), (2)} (Part 2 of 2)

Symbol	Parameter	Minimum	Maximum	Units
t_{CD2UM}	CONF_DONE high to user mode ⁽³⁾	175	437	μs
t_{CD2CU}	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
t_{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU} + (8576 \times \text{CLKUSR period})$	—	—

Notes to Table 53:

- (1) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.
- (2) t_{CF2CD} , t_{CF2ST0} , t_{CFG} , t_{STATUS} , and t_{CF2ST1} timing parameters are identical to the timing parameters for PS mode listed in Table 54 on page 63.
- (3) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on this pin, refer to the Initialization section of the “Configuration, Design Security, and Remote System Upgrades in Stratix V Devices” chapter.

Passive Serial Configuration Timing

Figure 15 shows the timing waveform for a passive serial (PS) configuration when using a MAX II device, MAX V device, or microprocessor as an external host.

Figure 15. PS Configuration Timing Waveform ⁽¹⁾**Notes to Figure 15:**

- (1) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (2) After power-up, the Stratix V device holds nSTATUS low for the time of the POR delay.
- (3) After power-up, before and during configuration, CONF_DONE is low.
- (4) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (5) DATA0 is available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings in the **Device and Pins Option**.
- (6) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (7) After the option bit to enable the INIT_DONE pin is configured into the device, the INIT_DONE goes low.

Table 60. Glossary (Part 2 of 4)

Letter	Subject	Definitions
G H I	—	—
J	JTAG Timing Specifications	<p>High-speed I/O block—Deserialization factor (width of parallel data bus).</p> <p>JTAG Timing Specifications:</p> 
K L M N O	—	—
P	PLL Specifications	<p>Diagram of PLL Specifications ⁽¹⁾</p>  <p>Note: (1) Core Clock can only be fed by dedicated clock input pins or PLL outputs.</p>
Q	—	—
R	R _L	Receiver differential input discrete resistor (external to the Stratix V device).

